

ABSTRACT OF THE DISCLOSURE

A non-contact tester for electronic circuits consists of an electronic circuit and independent scanning head, in combination. The electronic circuit includes a micro-fabricated wireless i/o cell and means for sending and receiving signals via the wireless i/o cell. The independent scanning head has a wireless i/o cell that is compatible with the wireless i/o cell on the electronic circuit. This enables data to be exchanged with the electronic circuit to confirm proper functioning of the electronic circuit.